

INTEGRATED MICROSCOPY AND GRAPHICS EXPERTISE

618-453-3730
imagesiuc@gmail.com

Rates

Personnel

How to Book

Equipment

Hours

Acknowledgment and Funding

Image Gallery

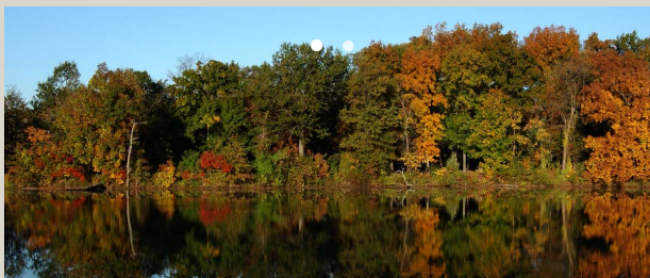
News

Contact Us

Integrated Microscopy and Graphics Expertise

750 Communications Drive
Carbondale, IL 62901
Hours: M-F 9:00am - 4:00pm

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HELPFUL LINKS

- [Office of Sponsored Projects Administration \(OSPA\)](#)
- [National Science Foundation \(NSF\)](#)
- [National Institute of Health](#)
- [Office of Vice-Chancellor for Research \(OVCR\)](#)

WHAT IS THE IMAGE CENTER?

The centrally located IMAGE facility provides training, technical service, and research in scanning electron, transmission electron, atomic-force, and light microscopy. Advanced capabilities include x-ray analysis, image analysis, and viewing of specimens under near-atmospheric conditions.



Members of MRS in a tour through the IMAGE Center

HOW TO BOOK

Booking an instrument in the facility can be done by emailing GA's at imagesiuc@gmail.com or 618-453-3730. Please provide the reservation time, user name, Principal Investigator and concerned BP number.

OUTREACH

DATE	School/Dept/Class	# of students	Instruments
April 26, 2019	SIU Day	TBD	SEM/TEM
April 24, 2019	Chem 575 (Characterization Chemistry Graduate course)	6 students	SEM/TEM
March 21, 2019	Carbondale High	12 students	SEM/TEM

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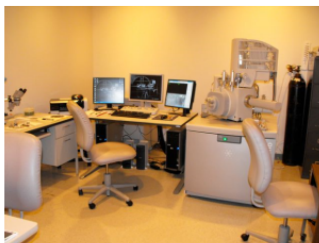
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FEI Quanta FEG 450 SEM with EDS detectors



High vacuum

- 0.8 nm at 30 kV (STEM)
- 1.0 nm at 30 kV (SE)
- 2.5 nm at 30 kV (BSE)
- 3.0 nm at 1 kV (SE)

High vacuum with beam deceleration option

- 3.0 nm at 1 kV (BD mode + BSED)
- 2.3 nm at 1 kV (BD mode + ICD)
- 3.1 nm at 200 V (BD mode + ICD)

Low vacuum

- 1.4 nm at 30 kV (SE)
- 2.5 nm at 30 kV (BSE)
- 3.0 nm at 3 kV (SE)

Extended vacuum mode (ESEM)

1.4 nm at 30 kV (SE)
 Magnification: 6 to 1,000,000x

SEM Detectors:
 ELS, BS, EDS, ETD, LFD and STEM

For wet samples:
 Environment-SEM and STEM

Hitachi H-7650 TEM



HC mode

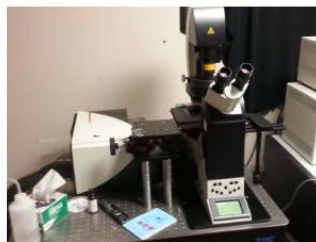
ZOOM-1 200x to 200,000x
 ZOOM-2 200x to 200,000x
 DIFF 0.05 m to 8.0 m
 F-Zoom 200x to 200,000x (option)
 F-DIFF 0.05 m to 8.0 m (option)

HR mode

ZOOM-1 4,000x to 600,000x
 ZOOM-2 4,000x to 600,000x
 DIFF 0.05 m to 2.0 m
 F-Zoom 4,000x to 600,000x (option)
 F-DIFF 0.05 m to 2.0 m (option)

LOW MAG mode 50x to 1,000x

Leica Confocal Inverted Microscope, Model: Leica TCS SP5



This instrument has six lasers and two PMT's. The microscope is controlled by a Leica software. A new high-speed camera is added to the microscope which can acquire images upto 25,000 fps. This instrument is available for use. Rate is \$ 40/hour

Park Scientific-Auto Probe CP Atomic Force Microscope



Denton Sputter Coater



Denton Evaporator



Leica Ultra Microtome



Leica Optical Microscope

